Special Issue

New Techniques of Machine Learning and Deep Learning in Text Classification

Message from the Guest Editors

Text classification is at the heart of a variety of software systems that process text data at a large scale. It performs fundamental tasks in natural language processing and is applied broadly for sentiment analysis, spam detection, and topic labeling. Nowadays, data can be easily collected from various sources with diverse formats, with text being one of the most common types of unstructured data. However, as data size grows exponentially, traditional technologies have become unable to handle such massive and unstructured data, leading to the emergence of big data in text classification and cutting-edge machine learning and deep learning techniques that can perform high-accuracy lower-level engineering and computation functions.

This Special Issue aims to bring together cutting-edge research from both academia and the industry focusing on new techniques for machine learning and deep learning for text classification. To this aim, we are calling for researchers with broad expertise in various fields to present their cutting-edge work as well as perspectives on future directions in this exciting field.

Guest Editors

Dr. Duy-Tai Dinh
The Kyoto College of Graduate Studies for Informatics, Kyoto 606-8225, Japan

Dr. Uday Kiran Rage
Institute of Industrial Science, University of Tokyo, Bunkyo City, Tokyo 113-8654, Japan

Deadline for manuscript submissions

closed (20 October 2023)

About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32, 20133 Milano, Italy

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